PCN Number:	20160630001	**PCN Date:**	Dec 13, 2016
Title:	DFAB VLCT Offload to SCT		
Customer Contact:	[PCN Manager]()	**Dept:**	Quality Services
Proposed 1st Ship Date:	June 13, 2017		

Change Type:

☐	Assembly Site	☐	Design	☐	Wafer Bump Site
☐	Assembly Process	☐	Data Sheet	☐	Wafer Bump Material
☐	Assembly Materials	☐	Part number change	☐	Wafer Bump Process
☐	Mechanical Specification	☒	Test Site	☐	Wafer Fab Site
☐	Packing/Shipping/Labeling	☐	Test Process	☐	Wafer Fab Materials
				☐	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments Incorporated is announcing the transfer of select high volume demand devices using VLCT tester in DFAB (Dallas South bldg. North Campus) to VLCT tester EBT/SCT (Dallas SC Building in North Campus).

Test programs are identical.

Test hardware configurations identical.

Reason for Change:

- Consolidate the VLCT tester to one probe facility
- Mitigate test capacity shortage in DFAB.
- Material test cycle time improvement.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

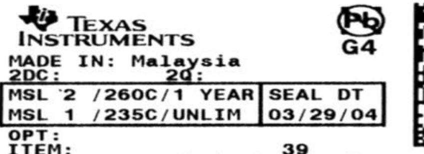
Current

Site	site code (20L)	country code (21L)
DFAB	DFB	USA

New

Site	site code (20L)	country code (21L)
SCT	**DM4**	**USA**

Example shipping label (not actual product label)



(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T)LOT: 3959047MLA
(4W) TKY(1T) 7523483SI2
(P)
(2P) REV: (V)
(20L) CSO: SHE (21L) CCO:USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected:			
SN0605104PJ-A	TPIC44L01DBG4	TPIC46L02DBG4	TPIC6C595DR
SN104217NSR-A	TPIC44L01DBR	TPIC46L02DBR	TPIC6C595DRG4
SN104479DWR	TPIC44L02DB	TPIC46L02DBRG4	TPIC6C595N
SN65HVD1040QDRQ1	TPIC44L02DBG4	TPIC6B595DW	TPIC6C595PW
SN65HVD1050AQDRQ1	TPIC44L02DBR	TPIC6B595DWG4	TPIC6C595PWG4
SN65HVD1050QDRQ1	TPIC44L02DBRG4	TPIC6B595DWR	TPIC6C595PWR
SN65HVDA1050AQDR-M	TPIC46L01DB	TPIC6B595DWRG4	TPIC6C595PWRG4
SN65HVDA1050AQDRQ1	TPIC46L01DBG4	TPIC6B595N	TPIC74100QPWPRQ1
TLC5941QPWPRQ1	TPIC46L01DBR	TPIC6C595D	TPIC74100QPWPRLRD
TPA6211A1TDGNRQ1	TPIC46L01DBRG4	TPIC6C595DG4	TPIC74101QPWPRQ1
TPA6211A1TDNVRQ1	TPIC46L02DB		TUSB1106IPWRQ1
TPIC44L01DB			

DFAB/SCT VLCT offload Correlation Report

Sedta Boorananut

06/15/16

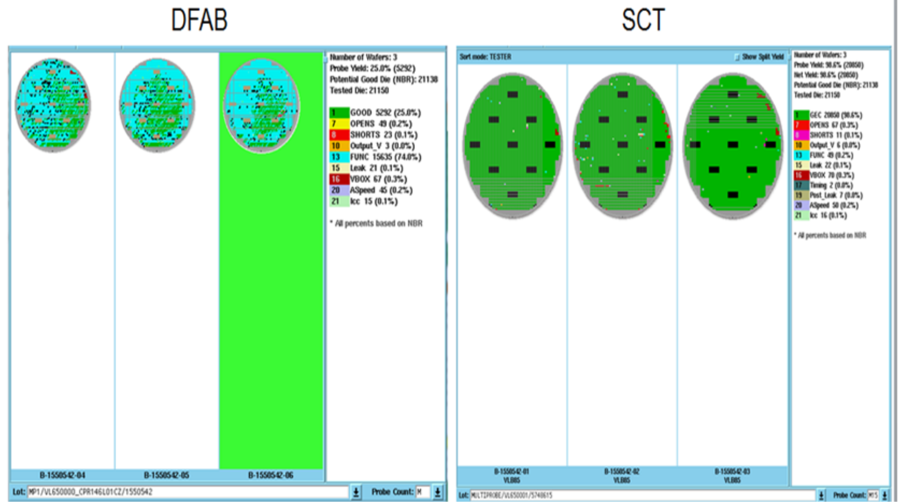
BPR146L01CZ8

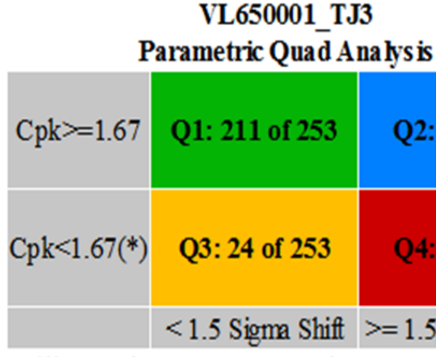
BLBFIC74100DZ8

BLBF1050ABZ8

TI Confidential – NDA Restrictions

SCT/DFAB Correlation Data– BPR146L01CZ8 offload to SCT



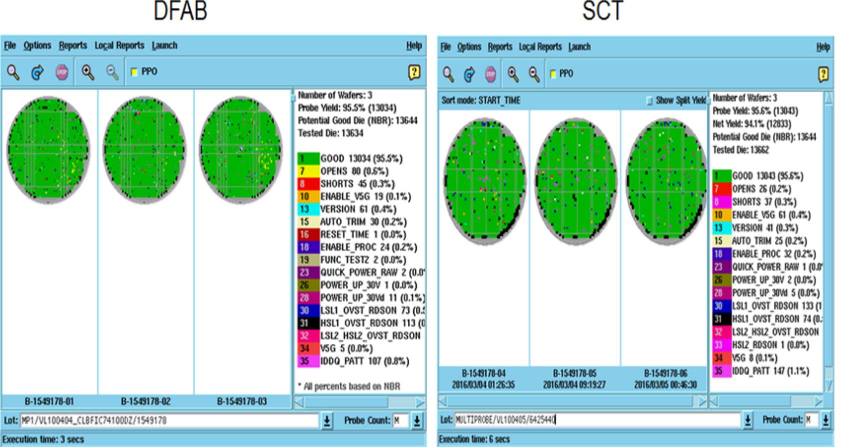


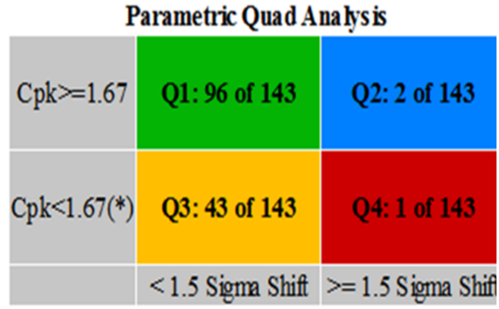
- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 7
- Click in a quad to view plots of the tests

- DFAB Yield 25% compared to SCT Yield 98.6%
- SCT has zero GEC due to bin13 on the VL650000 program (original program).
- SCT have to work on the VL650001program to address bin13 issue and address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1550542

TI Confidential – NDA Restrictions

SCT/DFAB Correlation Data– BLBFIC74100DZ offload to SCT

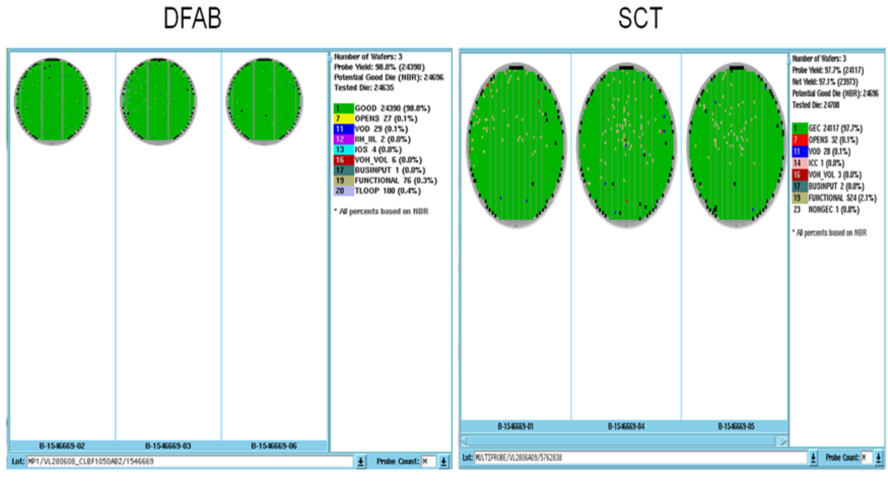


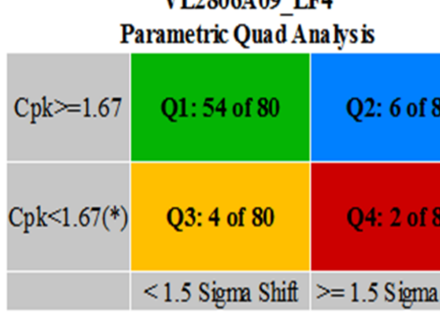


- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 1
- Click in a quad to view plots of the tests.

- DFAB Yield 95.5% compared to SCT Yield 95.6%
- SCT have to modify test program on the VL100405 program to address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1549178
- Most of the parameters shows the low Cpk and relate to the bin13.

SCT/DFAB Correlation Data– BLBF1050ABZ offload to SCT





- (*) or Cpk < 0.5 X Base Cpk
- Unclassified tests: 14
- Click in a quad to view plots of the tests.

- DFAB Yield 98.8% compared to SCT Yield 97.7%
- SCT have to modify test program on the VL280609 program to address the SCT automation issue (Change Temp type from Temp_25C_Deg to Temp_30C_Deg and add Pin List for Auto-Z routine.
- See the Parametric quad analysis on the follow link http://home.dal.design.ti.com/~a0864045/1546669/

TI Confidential – NDA Restrictions

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com